

AO8818



Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

The AO8818 uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V while retaining a 12V $V_{\rm GS(MAX)}$ rating. It is ESD protected. This device is suitable for use as a uni-directional or bidirectional load switch, facilitated by its common-drain configuration. Standard Product AO8818 is Pb-free (meets ROHS & Sony 259 specifications). AO8818L is a Green Product ordering option. AO8818 and AO8818L are electrically identical.

Features

 $V_{DS}(V) = 30V$

 $I_D = 7A \ (V_{GS} = 10V)$

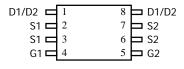
 $R_{DS(ON)}$ < 18m Ω (V_{GS} = 10V)

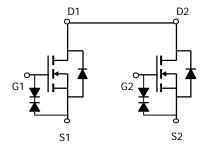
 $R_{DS(ON)} < 20m\Omega (V_{GS} = 4.5V)$

 $R_{DS(ON)}$ < 27m Ω (V_{GS} = 2.5V)

ESD Rating: 1500V HBM







Absolute Maximum Ratings T _A =25°C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		V_{DS}	30	V			
Gate-Source Voltage		V_{GS}	±12	V			
Continuous Drain	T _A =25°C		7				
Current ^A	T _A =70°C	I_{D}	5.5	Α			
Pulsed Drain Current ^B		I _{DM}	30				
	T _A =25°C	В	1.5	W			
Power Dissipation ^A	T _A =70°C	$-P_{D}$	0.96]			
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C			

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	64	83	°C/W			
Maximum Junction-to-Ambient A	Steady-State	$R_{ heta JA}$	89	120	°C/W			
Maximum Junction-to-Lead ^C	Steady-State	$R_{ heta JL}$	53	70	°C/W			

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V		30			V
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} =24V, V_{GS} =0V	V _{DS} =24V, V _{GS} =0V			1	^
			T _J =55°C			5	μΑ
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±10V	V _{DS} =0V, V _{GS} =±10V			10	μΑ
BV_{GSO}	Gate-Source Breakdown Voltage	V _{DS} =0V, I _G =±250uA		±12			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_D=250\mu A$		0.6	0.94	1.5	V
$I_{D(ON)}$	On state drain current	V _{GS} =4.5V, V _{DS} =5V		30			Α
R _{DS(ON)}	Static Drain-Source On-Resistance	V_{GS} =10V, I_D =7A			15	18	mΩ
			T _J =125°C		21	25	
		V_{GS} =4.5V, I_D =5A			17	20	mΩ
		V_{GS} =2.5V, I_D =4A			22	27	mΩ
g _{FS}	Forward Transconductance	V_{DS} =5V, I_{D} =7A			45		S
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V			0.74	1	V
Is	Maximum Body-Diode Continuous Currer	ent				2.5	Α
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz			880	1060	pF
Coss	Output Capacitance				130		pF
C _{rss}	Reverse Transfer Capacitance				90		pF
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz			1.3	2	Ω
SWITCHI	NG PARAMETERS		•		•		
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =15V, I _D =7A			11.6	14	nC
Q_{gs}	Gate Source Charge				1.9		nC
Q_{gd}	Gate Drain Charge				4.6		nC
t _{D(on)}	Turn-On DelayTime	V_{GS} =5V, V_{DS} =15V, R_L =2.2 Ω , R_{GEN} =3 Ω			8.7		ns
t _r	Turn-On Rise Time				13.7		ns
t _{D(off)}	Turn-Off DelayTime				36		ns
t _f	Turn-Off Fall Time				11		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =7A, dI/dt=100A/μs			16	20	ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =7A, dI/dt=100A/μs			7.7		nC

A: The value of $R_{\theta,JA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

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C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using $80\,\mu s$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

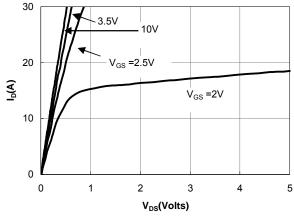


Figure 1: On-Regions Characteristics

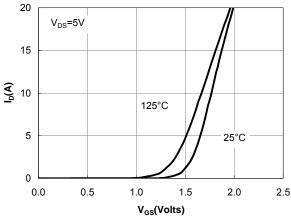


Figure 2: Transfer Characteristics

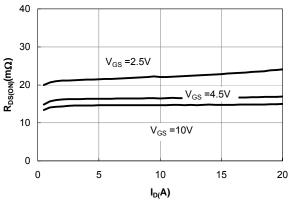


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

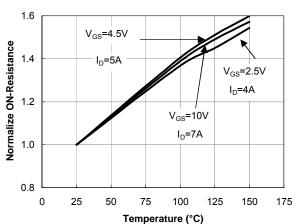
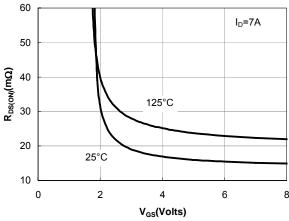
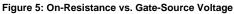


Figure 4: On-Resistance vs. Junction Temperature





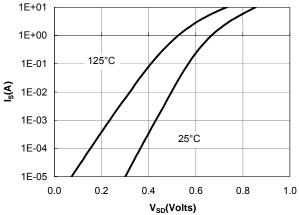
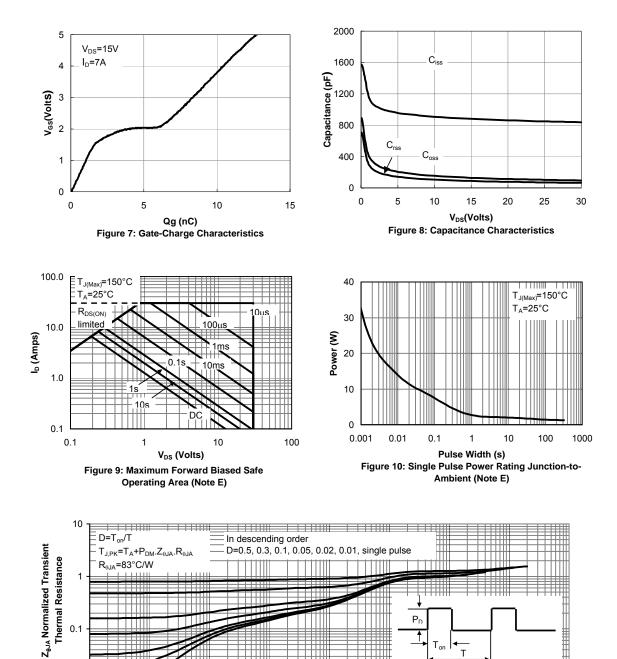


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance

0.1

1

10

100

1000

0.0001

0.001

0.01

0.01 + 0.00001